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SEIF NNOVATION Shanghai Emerging Industries Foundation

'3rd Generation Semiconductors' 第三代半导体论坛

The Development of SiC power devices

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www.cmventure.net



Momentum 14 Nov 2023



Challenges facing the silicon carbide industry chain

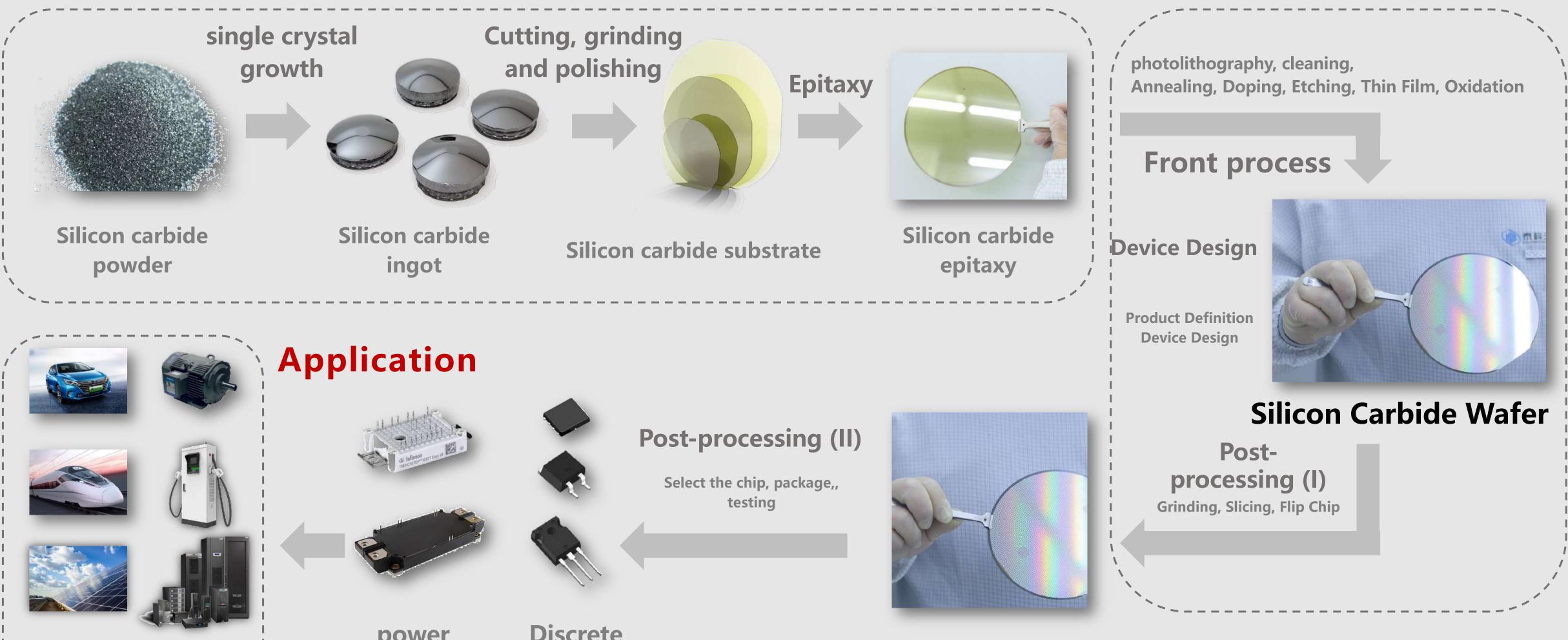


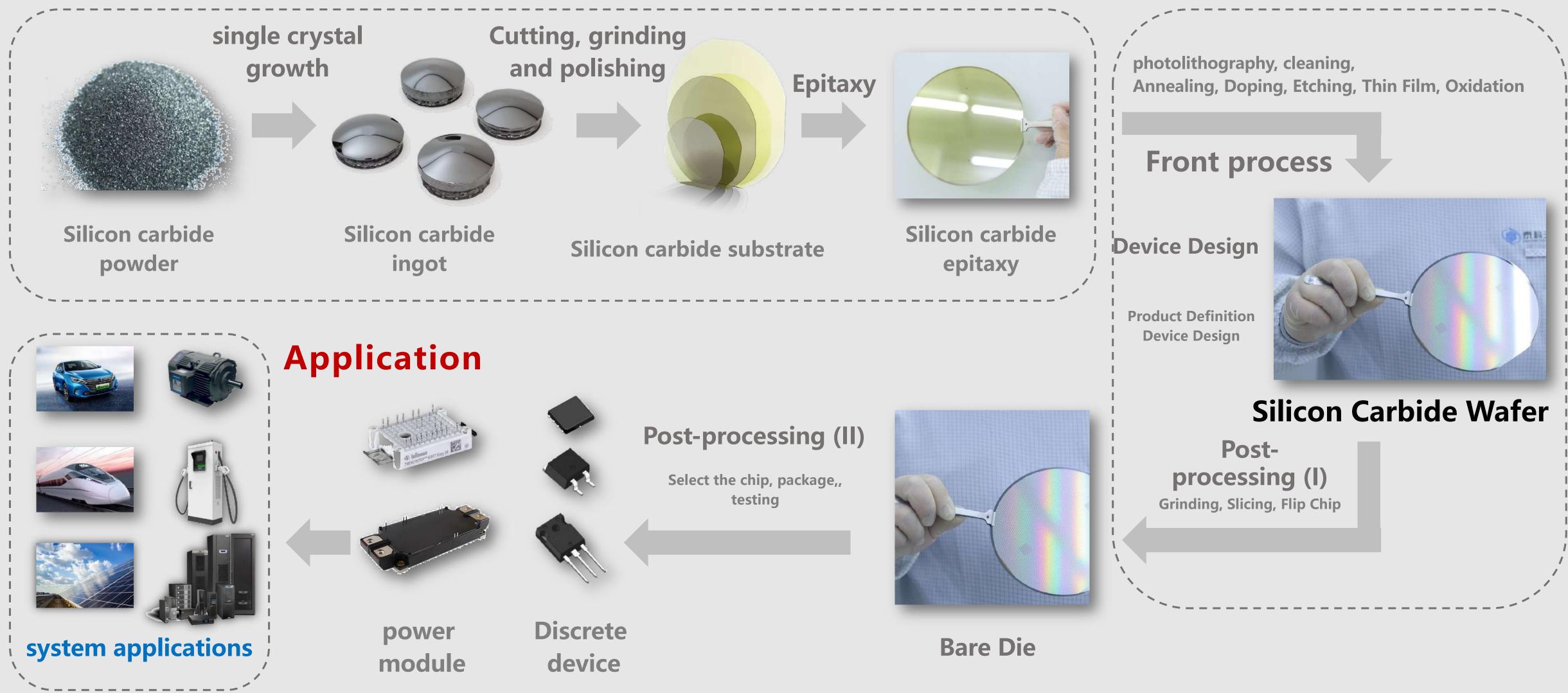




Silicon Carbide Supply Chain

Material

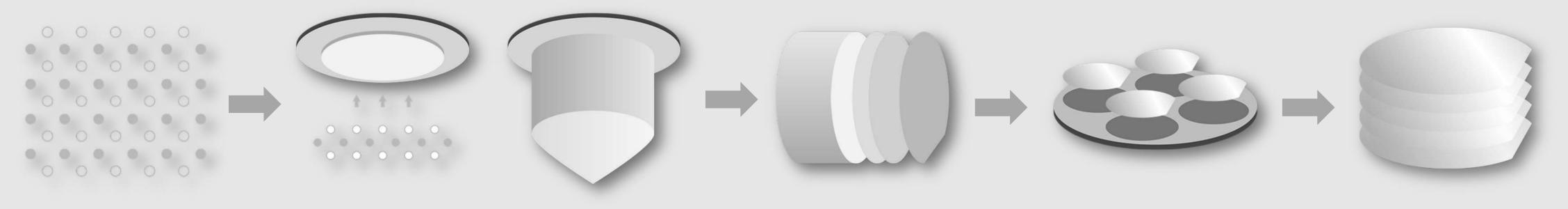




Device

3





SiC powder

crystal growth

Single crystal growth cycle is long, easy to include crystal defects

- PVT 0.2-0.4mm/h, HT-CVD 0.3-1.0mm/h, LPE 0.5-2mm/h
- Defects include microtubules, crystal inclusions, dislocations, stacking faults, etc., and there is mutual influence and evolution

Substrate quality directly affects downstream epitaxy and devices

- Good quality of substrate can reduce defect in epitaxial growth
- If there are defects on substrate will lead to the degradation of device performance, resulting in an increase in onresistance and leakage current.

Sic Material

cut

grinding and polishing

epitaxy

Difficult to control

• **Thermal field control**– The growth heat field is above 2300°C, and there is a temperature gradient, which leads to defects such as dislocation and stacking fault

Crystal control – SiC includes more than 200 crystal forms, and only 4H crystal form is required for mainstream production, which is difficult to control stably

Doping control – The introduction of external impurity must be strictly controlled to obtain directional doped conductivity-type crystals **Surface control** – High hardness and brittle material, there are problems such as easy cracked

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Device Design and Manufacturing

sputtering machine oxidation furnace annealing furnace
Material property Processes Difficulties Industr
Silicon carbide has no diffusion, and doping requires high-energy implantation. Generally, the implantation energy is 300KEV, and it even needs to be second-order to more than 700KEV.
difficult to diffuse Need to implant AL, and high temperature annealing process is required Need to implant AL, and high temperature annealing process is contaminated and p
double The gate oxide process has to face the reaction of carbon atoms, which will form carbon-related impurities, which requires a high- temperature oxidation process, which is very difficult.
transpare ntIt is difficult to adapt to the lithography process, and it is difficult to position the equipment when wafer transferred and taken.Unstable fragmentation rate
hard Dry etching is difficult, and the etching process is one of the top- level difficulties of the silicon carbide devices process. Cannot be guarante
crisp It is easy to crack when transferring or drying , and it is difficult Low production effi



ialization problem

cost and low tape-out efficiency

silicon industry, and the process quipment support are relatively perature furnaces are easily to be oor long-term stability

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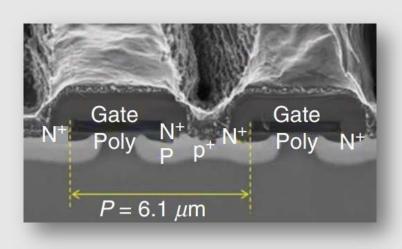
s, low transfer efficiency, high

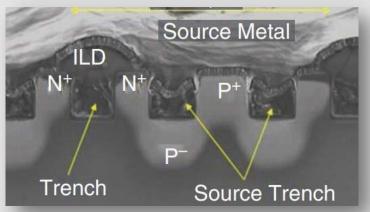
and stability of the deep etching

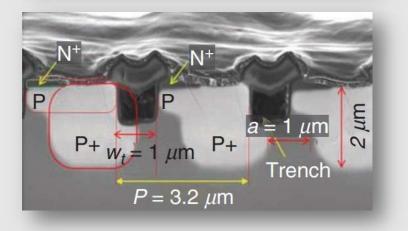
iency and high fragmentation rate

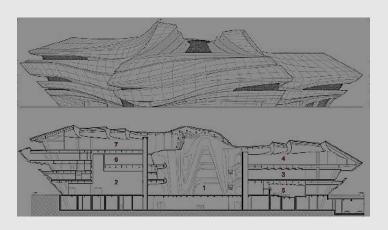
Design and Manufacturing

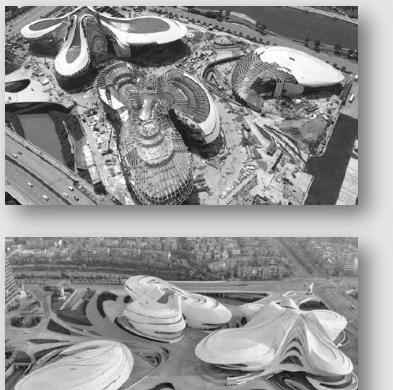
- **Device Design** Device structure design, selection of some process conditions, simulation verification
- Wafer fabrication Turn designs into reality based on equipment and mature process capabilities
- Weak foundation Insufficient knowledge of materials, inaccurate models, large differences between design and actual
- Cant meet design demand Limited by insufficient process capability, unable to meet design requirements



















Technical barriers bring development constraints

Device level: wafers are not easy to do

high temperature process and characteristic process need to be integrated and explored **MOSFET Threshold Voltage Drift Degradation with Temperature and Time**

Insufficient production capacity will not be alleviated in the short term There are still many defects in the material Long cycle and high cost Affect device reliability and yield

not enough data **Feedback exposes** material issues

> Not enough usage to reduce costs Insufficient data feedback to expose material issues

Material level: the material is hard to

grow high temperature growth, low production efficiency of vapor deposition defects are numerous and complex, the threshold for industrialization is high, and production capacity increases slowly

Insufficient production capacity will not be alleviated in the short term **Price drop is limited**

Material, process and application technology breakthrough threshold is high, the upstream and downstream feedback closed-loop is time-consuming and labor-intensive

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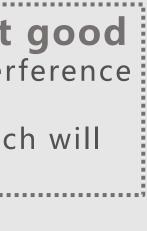
Insufficient production capacity will not be alleviated in the short term **Price drop rate is limited**

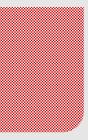
There is not enough demand volume to reduce costs, Not enough data feedback to improve the device

Expensive, can't afford it High failure rate, dare not use

> Some parameters of the device are not good enough further difficulty in use

Application level: high-speed use is not good High-frequency applications generate various interference and crosstalk in the circuit Silicon carbide MOSFET is falsely turned on, which will lead to power application prolem







The Road to SiC Industrialization in China







京科天海 Industrialization Development Issues of SIC Devices in China **Criteria for the success of industrialization**

Low cost, high quality, high volume

planned layout **Investment scale**

actually achieved **Production capacity**

achievable Supply Capacity

available Market revenue

Its own industrial technology level is immature

The process and products are immature and have not been verified by large-scale applications

The ability of upstream and downstream industries to cooperate is immature

The substrate material cannot be supplied, the cost cannot be reduced, and the downstream products cannot be sold by themselves

Industry status determines the small scale

Being crushed by foreign manufacturers, customers are reluctant to be guinea pigs and have been in a spare tire position for a long time



The fundamental contradiction between slow industry and urgent capital return

The main contradiction of slow upstream maturity and rapid downstream demand growth

The practical contradiction of slow output and urgent planning





package

wafer

design

epitaxy

DS

Ibstrate

Fabless and Foundry

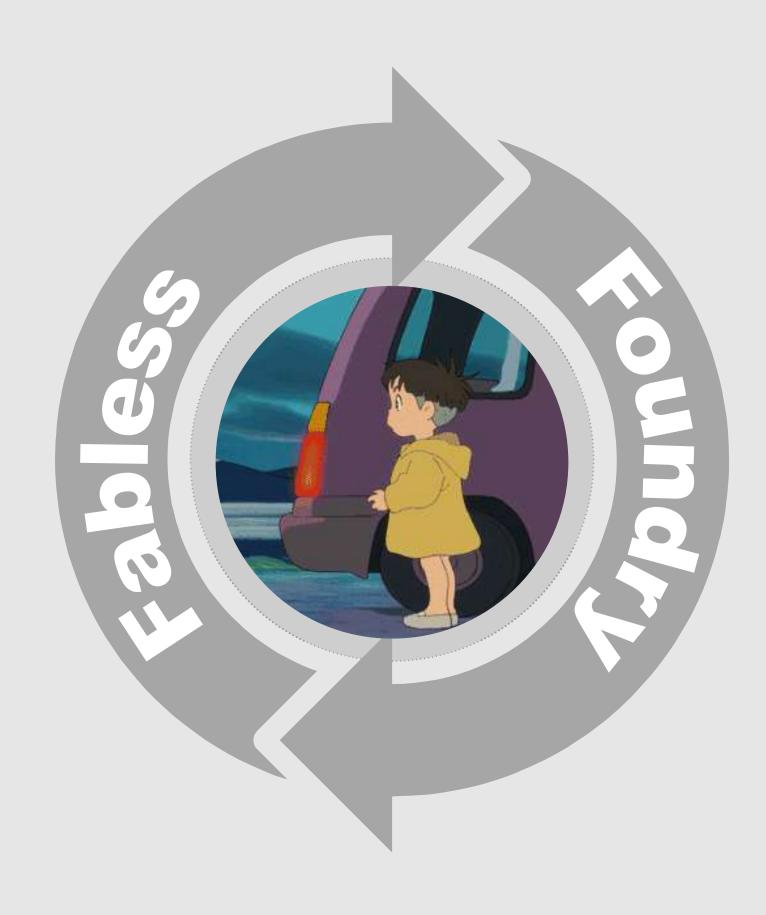
International

Fabless

- Asset-light, less investment, less burden
- Focus on device design
- Fast product introduction based on Foundry process capabilities

Chinese Fabless

- Cooperation with international and Chinese Foundry partners
- Some companies stick to Fabless
- Some enterprises have transformed to IDM



International

Foundry

- start early
- Relatively mature process technology

Chinese Foundry

- started late
- The process is not yet mature









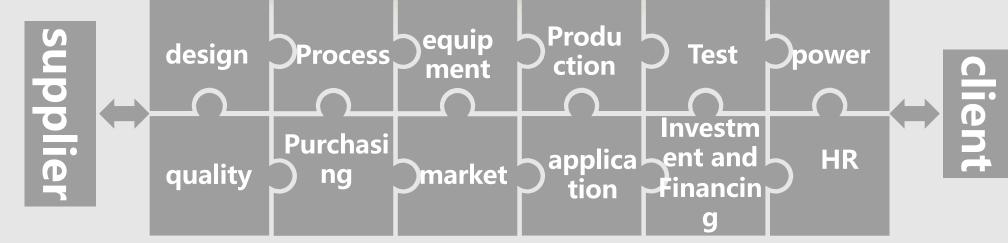


Product differentiation

more secure supply

Master the core craft

Form a system, seek oordination, and practice hard



Don't ask "advantages", focus on "shortcomings"

ackage

wafer





A rare opportunity in the industry window in ten years, hurry up to invest and build a factory Seize the wind of the industry and grasp the big cake of the market outbreak

The size of the layout is too large

- The amount of investment is too large, the burden is too heavy, and the operating cost is extremely high
- Rapid blood loss, cash flow breaks

The scale of the layout is not enough

- Insufficient scale effect and low customer acceptance
- High device cost and insufficient market advantage
- Repeated investment is timeconsuming and expensive, and new investment cannot be attracted

Annual production capacity	Major equipment set Number	clean room area (100, 1000, 10,000 level)	Land	Basic operating cost per year	fixed deprecia
50,000 wafer	100 sets	3000 m²	40,000m²	~40 million	~4(millio
100,000 wafer	200 sets	7000m²	60,000m²	~100 million	~10 millio
200,000 wafer	400 sets	12,000 m²	100,000m²	150 million	~15 millio











The whole industry chain

Control all aspects of the industrial chain and become an international giant



2021.10







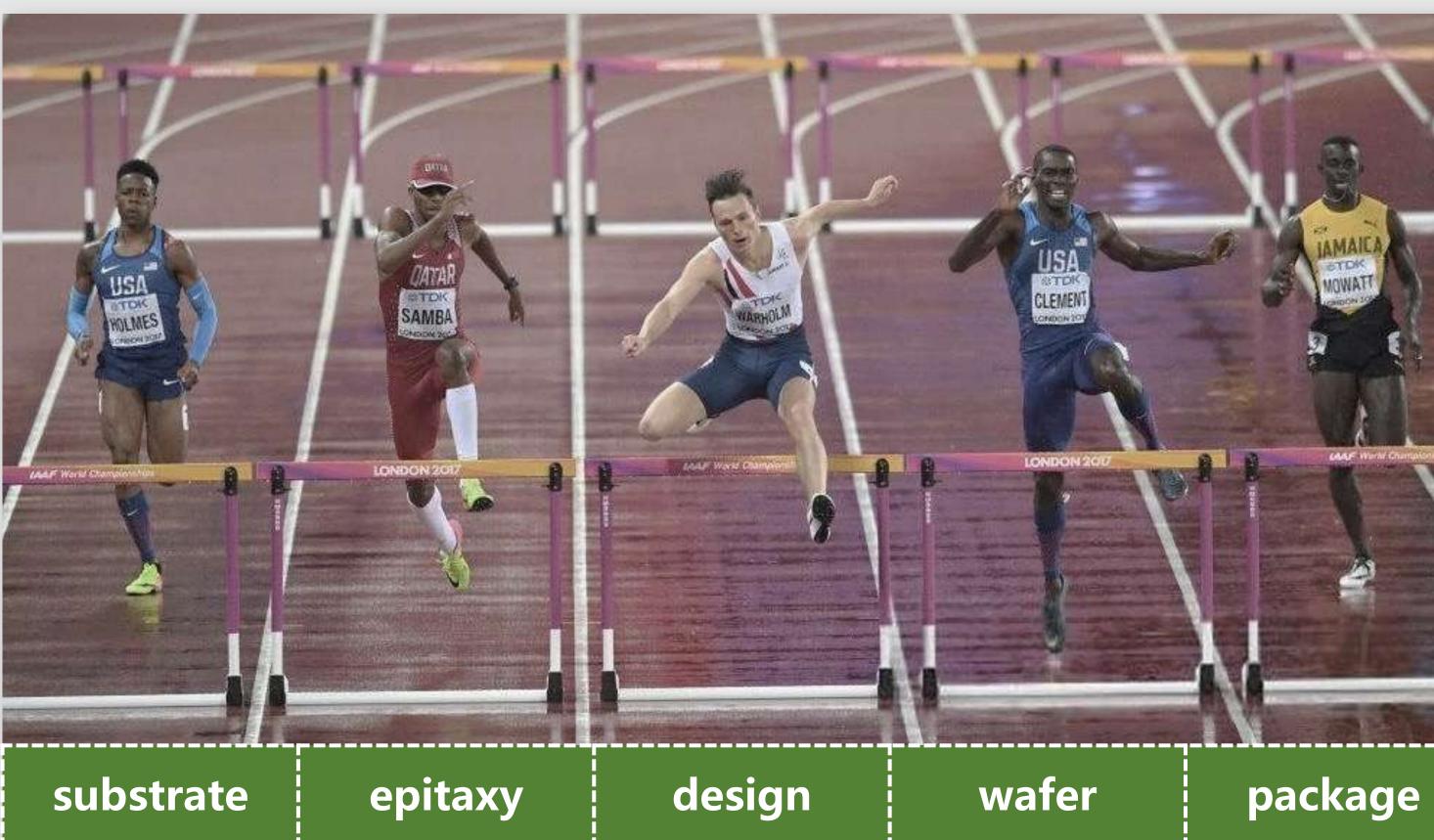
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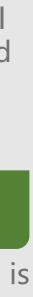
Development Route of Domestic Device Industrialization



- through a long time
- longer payback period

- Need to solve many problems asap otherwise conflicted company may not cooperate with them

GPT CONFIDENTIAL



• Strong anti-risk ability



Global Power Technology Co., Ltd.











GPT's IDM model

The third generation semiconductor



Development Vision

Filling the gap in China's silicon carbide field.Leading the core technology for the next 50 years



Changsha 6-inch wafer line Established in 2019, mass production in 2021 The first-phase investment is 300 million yuan, 60,000 6-inch wafers per year



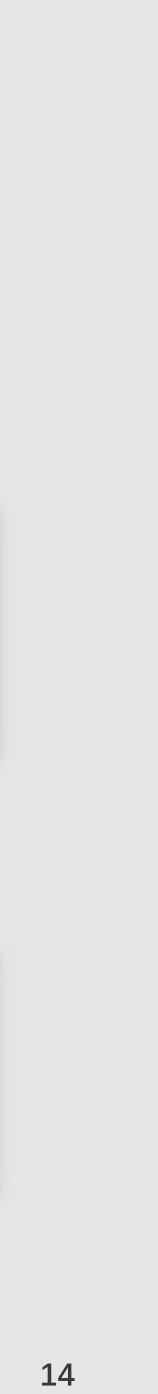
Beijing R&D Center started in 2022



Changsha discrete device packaging line Q1 start in 2022, 35kk/year



Beijing 4-inch wafer line Established in 2011, mass production in 2013 Investment of 120 million yuan, 8,000 4-inch wafers per year





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6-inch silicon carbide wafer production line Mass production and delivery in September 2021

Launch in 2019 The first phase investment is 300 million yuan The first phase of 6-inch wafers 60,000 / year

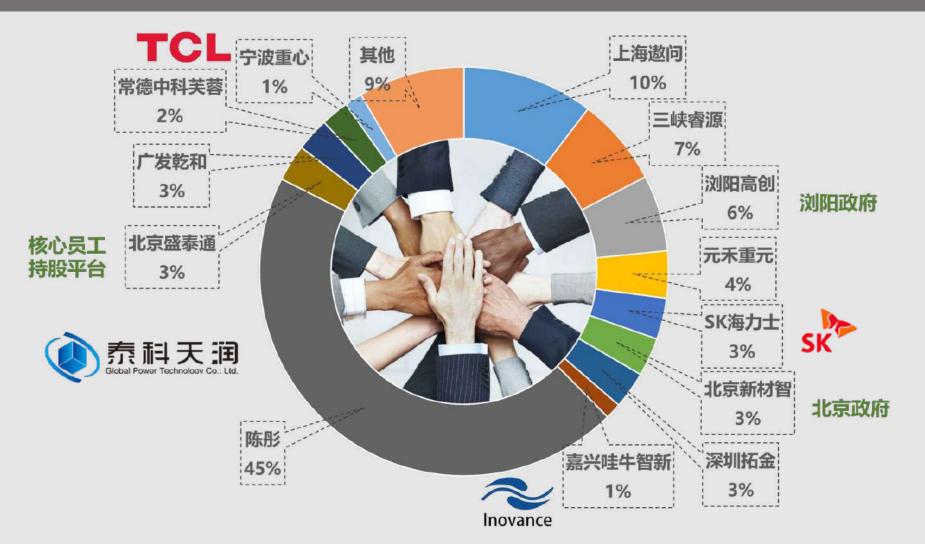


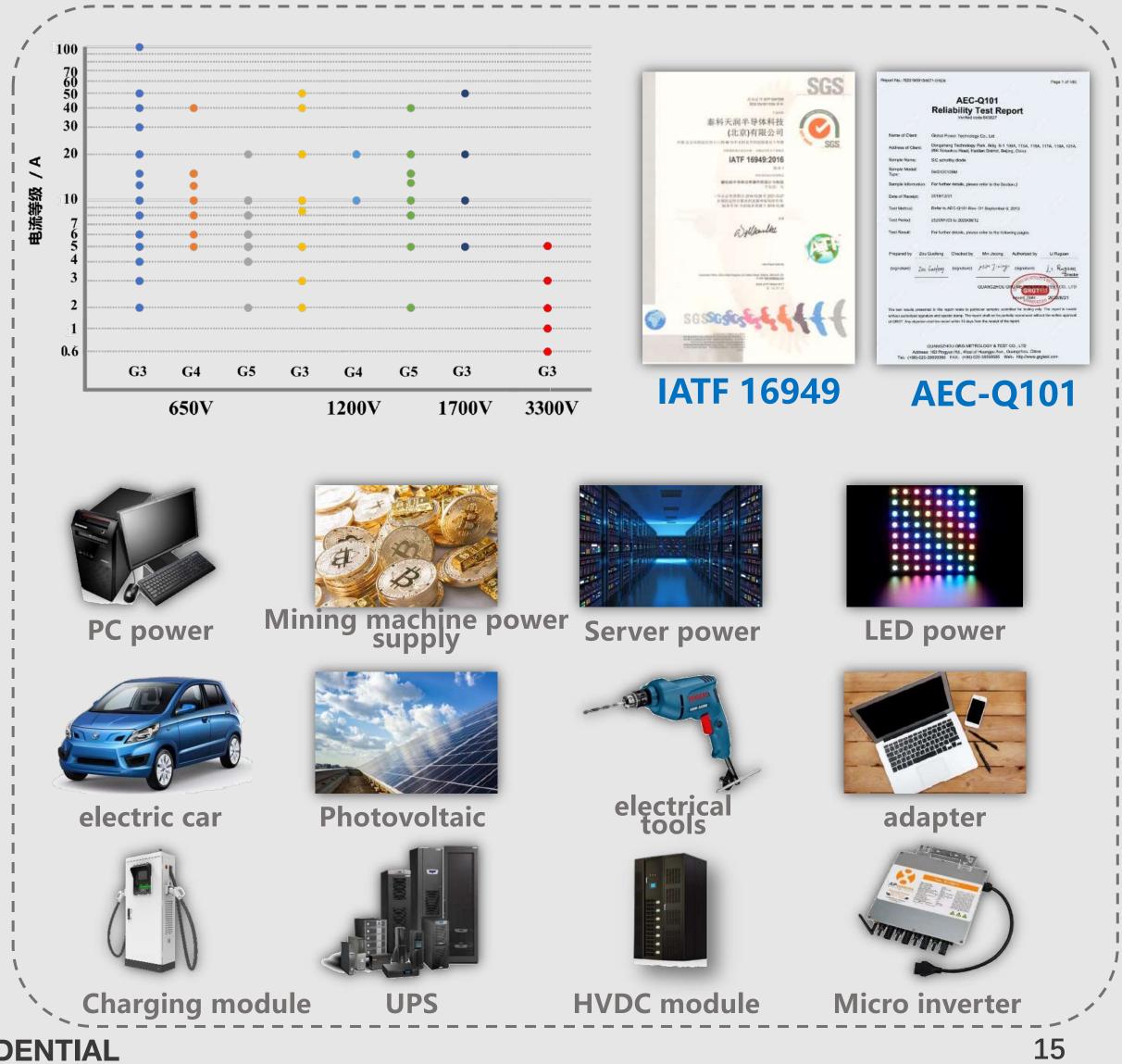


Complete the D round of investment in 2021 E-round investment is about to start

Capital continues to be optimistic Support from upstream and downstream parties











Global Power Technology Co., Ltd(GPT) 泰科天润半导体科技(北京)有限公司





